

ABSTRACT

The invention is directed to repairing of a defective portion caused by a short circuit without generating a dark spot by a pin hole. Laser beams are irradiated to an irradiating region set in a peripheral region of a foreign substance. This prevents damaging of an organic EL element which the foreign substance adheres to and formation of the pin hole. By irradiating laser beams to the peripheral region at a distance from the foreign substance, energy of the laser beams spreads concentrically around the irradiating region, and is also supplied to the foreign substance indirectly. Therefore, the high resistive region can be formed between an anode layer and a cathode layer so that the defective portion caused by the short circuit by the foreign substance can be repaired.